	N Number: 20200124000.1A PCN Date: Mar 18, 202					<b>te:</b> Mar 18, 2020	
	Qualification of TI Malaysia as an additional Assembly and test site for Select Devices						
,							
		<u>Manager</u>	Dept:	,	ted Sam	nlo I	Date provided at
Proposed 1 <sup>st</sup> Ship	Date:	Apr 30 2	2020		Availabili		sample request
Change Type:					tvanabiii	icy:	sample request
Assembly Site			Design			Nafer	Bump Site
Assembly Proces				a Sheet Wafer Bump Mate			
Assembly Mater				number change Wafer Bump Pro			
Mechanical Spec		1   X					
Packing/Shippin				st Process		Wafer Fab Materials	
<u> </u>	J,						Fab Process
			PCN	Details			
<b>Description of Cha</b>	nge:						
Revision A is to ann		the addition	on of nev	w devices that w	ere not in	rclude	d on the original
							_
PCN notification. These new devices are highlighted and <b>bolded</b> in the device list below expected first shipment date for these new devices will be 90 days from this notice (June				notice (June 18,			
2020) for these new	y added	d devices	only. Th	e proposed 1 <sup>st</sup> sh	nip date o	f Apr	30, 2020 still
applies for the origin	al set of	f devices.					
Texas Instruments is							
-			assembly and test site for the list of devices below. There are no construction differences				
between the current and new site.							
between the current	and nev	w site.					
			:		.l		
Test coverage, insert			will rema		th current	testir	ng and verified with
			will rema		th current	testir	ng and verified with
Test coverage, insert test MQ.	ions, co		will rema		:h current	testir	ng and verified with
Test coverage, insert test MQ.  Reason for Change	ions, co		will rema		:h current	testir	ng and verified with
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Test coverage, insert test MQ.  Reason for Change Continuity of Supply Anticipated impact	ions, co	onditions v		iin consistent wit			
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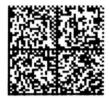
TEXAS INSTRUMENTS

MADE IN: Malaysia 2DC: 20:

MSL 2 /260C/1 YEAR SEAL DT 1 /235C/UNLIM 03/29/04

OPT: ITEM:

(L)T0:3750



(1P) SN74LS07NSR (a) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(P) (2P) REV: (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MVC

(23L) ACO: MYS

## **Product Affected:**

MSP430FR2422IPW16	TCAN1042HD	TCAN1042HVD	TCAN1051HGVD
MSP430FR2422IPW16R	TCAN1042HDR	TCAN1042HVDR	TCAN1051HGVDR
MSP430FR2512IPW16	TCAN1042HGD	TCAN1051HD	TCAN1051HVD
MSP430FR2512IPW16R	TCAN1042HGDR	TCAN1051HDR	TCAN1051HVDR
MSP430FR2522IPW16	TCAN1042HGVD	TCAN1051HGD	
MSP430FR2522IPW16R	TCAN1042HGVDR	TCAN1051HGDR	



TI Information Selective Disclosure

### **Qualification Results**

### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TCAN1051DQ1	Qual Device: TCAN1042DQ1	Qual Device: TCAN1042HVDQ1	Qual Device: TCAN1051VDQ1
AC	Autoclave 121C	96 Hours	-	1/77/0	1/77/0	1/77/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	1/77/0	1/77/0	1/77/0
HTOL	Life Test, 150C	300 Hours	-	1/77/0	1/77/0	1/77/0
HTSL	High Temp Storage Bake 175C	500 Hours	-	1/45/0	1/45/0	1/45/0
TC	Temperature Cycle, -65/150C	500 Cycles	1/77/0	1/77/0	1/77/0	1/77/0
WBP	Bond Pull	Wires	1/30/0	1/30/0	1/30/0	1/30/0
WBS	Wire Bond Shear	Wires	1/30/0	1/30/0	1/30/0	1/30/0

- QBS: Qual By Similarity
- Qual Devices TCAN1042DQ1, TCAN1051VDQ1, TCAN1051DQ1 and TCAN1042HVDQ1 are qualified at LEVEL1-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV, 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

# **Qualification Results**

Approved: 04-Mar-2020

### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: MSP430FR2522IPW16
AC	Autoclave 121C	96 Hours	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	3/77/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0
WBP	Bond Pull	Wires	3/228/0
WBS	Ball Bond Shear	Wires	3/228/0

- QBS: Qualification By Similarity
- Qualification Device MSP430FR2522IPW16 is qualified at Moisture Sensitivity LEVEL2-260C.
- Preconditioning was performed for Autoclave, Biased HAST, Temperature Cycle, and HTSL.

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

#### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

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USA	PCNAmericasContact@list.ti.com
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